

### **HCAL Front End Electronics**

### **Theresa Shaw**

CMS HCAL Electronics Project Engineer

### **CMS Electronics Week**

May 18, 2001



### **Electronics Overview**

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### **Electronics**

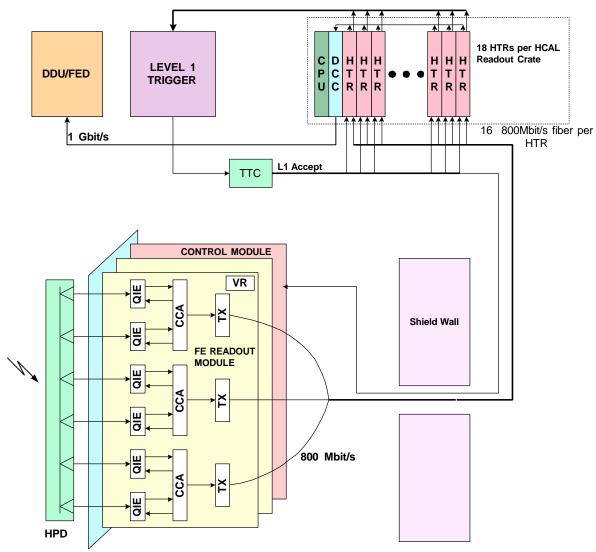
- System Overview
- Packaging
- Power
- Backplane
- Readout Module (RM)
- ASICs



## **FE/DAQ Readout**

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## **Packaging**

Η Α

### HB, HE, and HO will be packed in custom Readout BoXes (RBX)

### HF will be packed in standard Eurocard Crates

### **Crates Provide**

- Power
- Cooling
- Clock distribution
- Slow Controls Communication

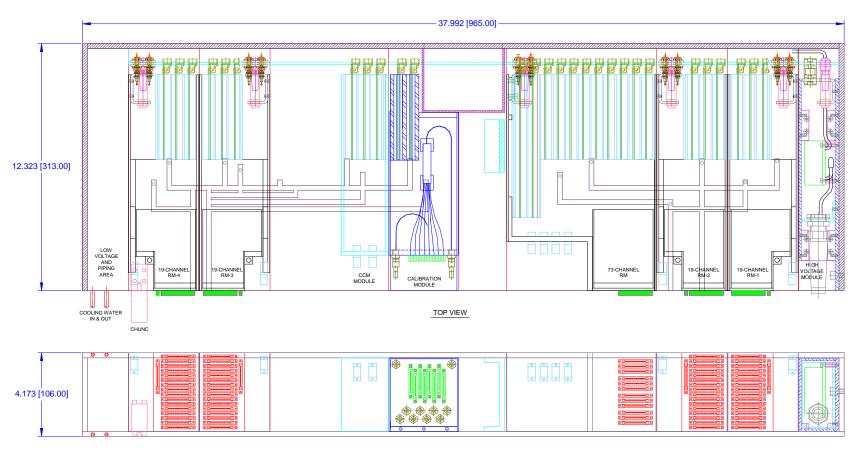


### **HB RBX**

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### 36 HB RBXs

### 4968 Channels



FRONT VIEW

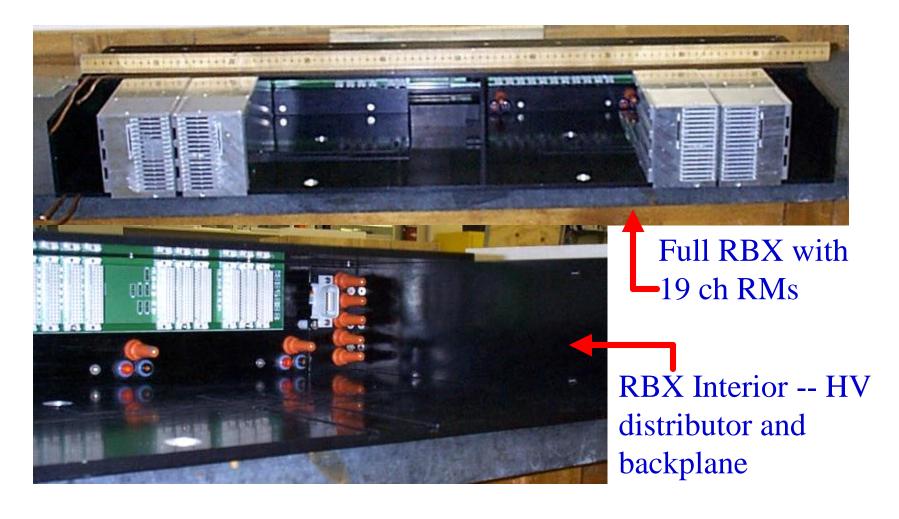
HB RBX COMPOSITE ASSEMBLY DRAWING

R. FOLTZ, FERMI LAB J. MARCHANT, UNIV. OF NOTRE DAME AS OF 23 FEBRUARY 2001 9 AM CST



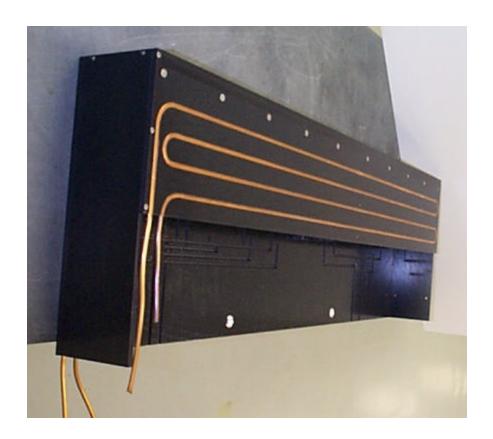
## **HB RBX Assembly**

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## Cooling Routing on RBX enclosure outer surface





# HB RBX Module Routing Channels

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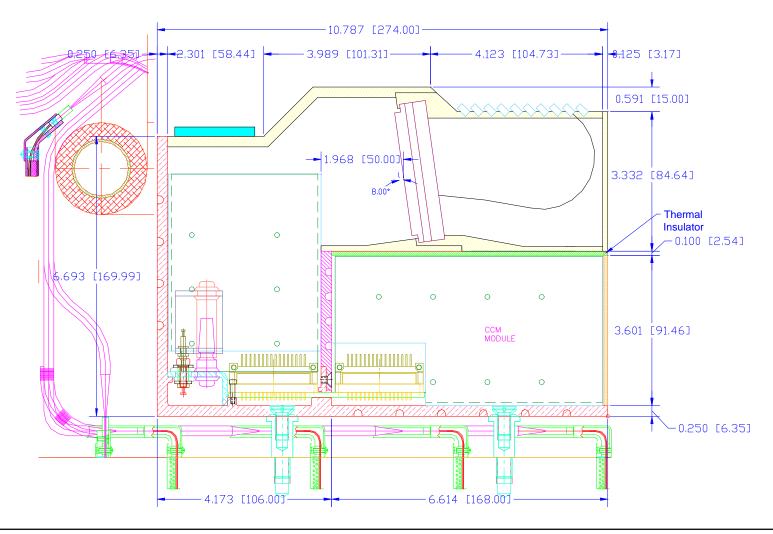


## HE RBX (r,z) view

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### 36 HE RBXs

### 3672 Channels



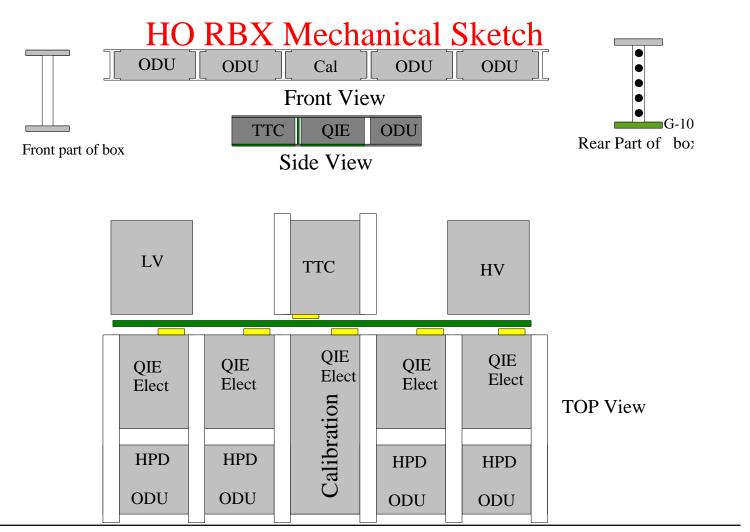


## **HO RBX Concept**

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### 36 HO RBXs

### **3744 Channels**





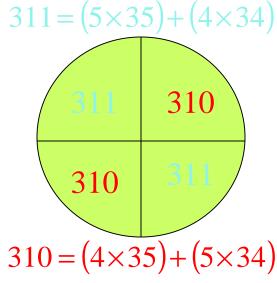
### **HF Channel Count**

H C A L

2484 Channels (includes "ECAL" & "TC")

1242 Channels per end

310 ½ Channels per quadrant (4 crates on each end)



51 3/4 Readout cards per crate

(6 QIE per card)

Structure

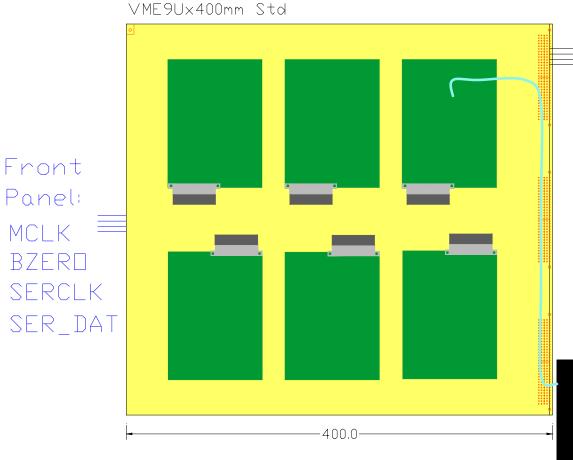
⇒ need 52 Readout cards per crate



## HF 9U Packaging **Proposal**

Н Α

## 6x6=36 channels



Backplane Signals: Power: V1,V2,V3 RFSFT+/-

External coax cabling from PMT input to readout card (36 total)

### Multisignal microcoax connector

						RSITY esign		cilit	— :у
Drawn By:	J. Rohlf	9U	VME	Мо	the	rboar	٠d		
		Pre	elimino	iry	HF	Read	ou	t	
		FILEN	IAME.EXT			1/30/01		REV:	



## HF 3U Packaging **Proposal**

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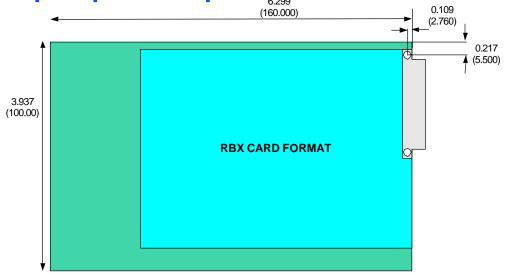
Produce Readout Cards in 3U Format

**Use Commercial 3U Crate** 

**Produce Custom Backplane (similar to HB, HE and HO)** 

- 18 slots for Readout Cards (108 channels)
- 3 slots for Clock and Control Modules

=>3 3U crates per quadrant per end



**Readout Module Dimensions** 3U Eurocard Format



## **Power Consumption**

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#### **Power Consumption**

HO+/- - 135 W HB - 298 W HE - 205 W HO-0 - 189 W 17A@6.5V 23A@6.5V 10A@6.5V 16A@6.5V

33A@4.5V 21A@4.5V 21A@4.5V 15A@4.5V

			CURRENT	and POW	ER at BOA	RD LEVEL					
EE Boord	QTY/BRD			POWER C	ONGLIDITIC	AN I		IDLING CURI	DENT		TOTAL
FE BOATU	Q11/DKD	VOLTAGE	5			3.3	5		2.5	3.3	IOIAL
Chips		VOLTAGE	5	5	2.5	3.3	5	5	2.5	3.3	
			0.0	0.4							
QIE	6		0.2	0.4		0.0					
CCA	3					0.3					
Serializer	3				0.5						
LV regulate	3						0.025	0.025		0.025	
Current / E	Board		0.265	0.505		0.897727					
Total Powe											9.044773
Calibratio	n Module	(There are	two boards	per module	e)						
		VOLTAGE	5	5	2.5	3.3	5	5	2.5	3.3	
Chips											
QIE	3		0.2	0.4							
CCA	3					0.3					
Serializer	2				0.5						
11/							0.005	0.005		0.005	
LV regulate	3						0.025	0.025		0.025	
Current / N	/lodule		0.145	0.265		0.697727					
Total Powe	er / Module										5.804773
ССМ											
		VOLTAGE				3.3					
Chips						5					
LV regulate	ors										
Current / E	Doord					4.545450					
						1.515152					0.040404
Total Powe	er / Board										6.818182

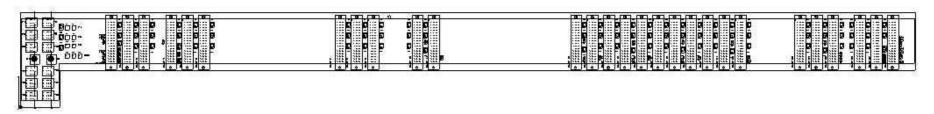


## **HB Backplane Function**

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### **Backplane**

- ~87 CM LONG
- Provides Power
- Distributes 40 MHz Clock (3 load max)
- Provides path for RBXbus (serial communication bus)
- Temperature feedback





### **Backplane Low Voltage Power** Connector

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#### Product Facts

"Inverse-sex" design meets IEC 950 safety requirements

Current rated at 7.8 amperes per contact, 23.5 amperes per module, fully energized

Sequenced right-angle headers available for "make-first/break-last" applications

**ACTION PIN press-fit contacts on both headers and receptacle** 

Contacts designed for up to 250 mating cycles

Recognized to U.S. and Canadian requirements under the Component **Recognition Program of Underwriters Laboratories Inc.** 

#### Universal Power Module

#### Low Voltage Distribution

3 Backplane Voltages

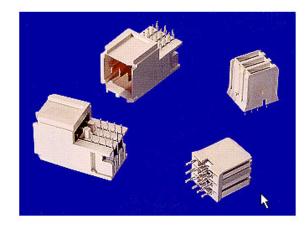
V1 (3 Universal Power Module Connectors for V1)

V2 (2 Universal Power Module Connectors for V2)

V3 (1 Universal Power Module Connectors for V3)

GND (6 Universal Power Module Connectors for GND)

Connectors allow for power sequencing





## **Backplane Connectors**

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#### Type C and Enhanced Type C Assemblies

Minimum adjacent mounting space required:

12.7 [.500]

**Current Rating:** 

Per DIN 41612\*

**Voltage Rating:** 

250 VAC

**Dielectric Rating:** 

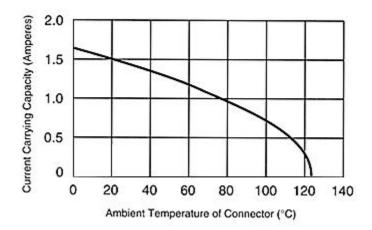
1000 VAC

**Contact Resistance:** 

15 milliohms initial at 100 ma and 50 mv, open circuit



Types B, C, Q and R per DIN 41612





### **FE Card Pinout**

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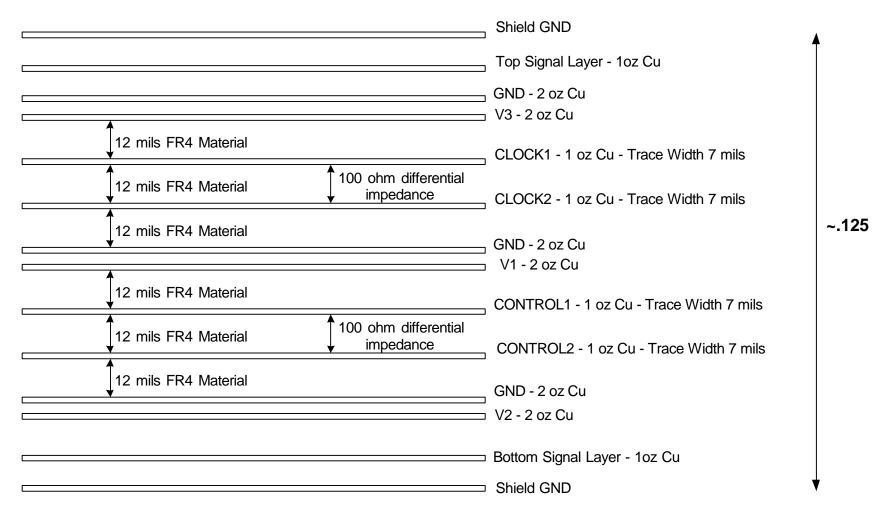
### **READOUT Card Slot**

Pin Number	Row A	Row B	Row C
1	GND	GND	GND
2	V1	V1	V1
3	GND	GND	GND
4	V2	V2	V2
5	GND	GND	GND
6	V3	V3	V3
7	GND	GND	GND
8	MCLK+	D0_CALIB	RESERVED
9	MCLK-	GND	GND
10	GND	GND	TEMP
11	GEO_ADDR(0)	GND	GND
12	GEO_ADDR(1)	GND	RSVD(1)
13	RESET+	GND	RSVD(2)
14	RESET-	GND	SERCLK+
15	BZERO+	GND	SERCLK-
16	BZERO-	GND	SER_DAT



## **Backplane Stack-up**

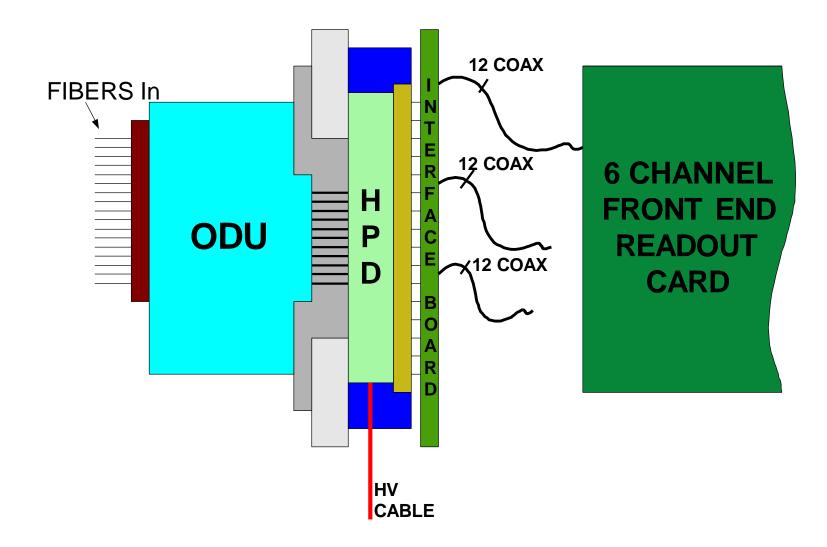
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### Readout Module **Overview**

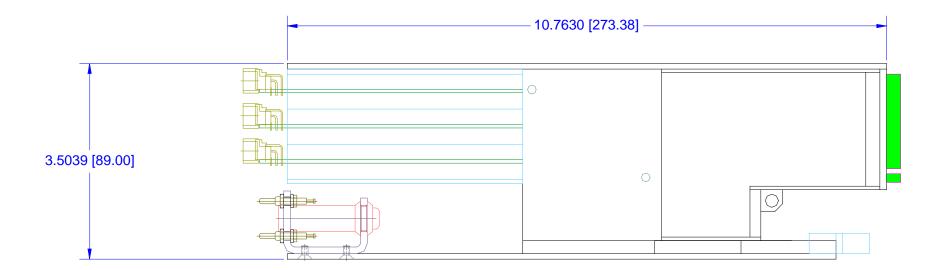
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### **RM-19 Plan View**

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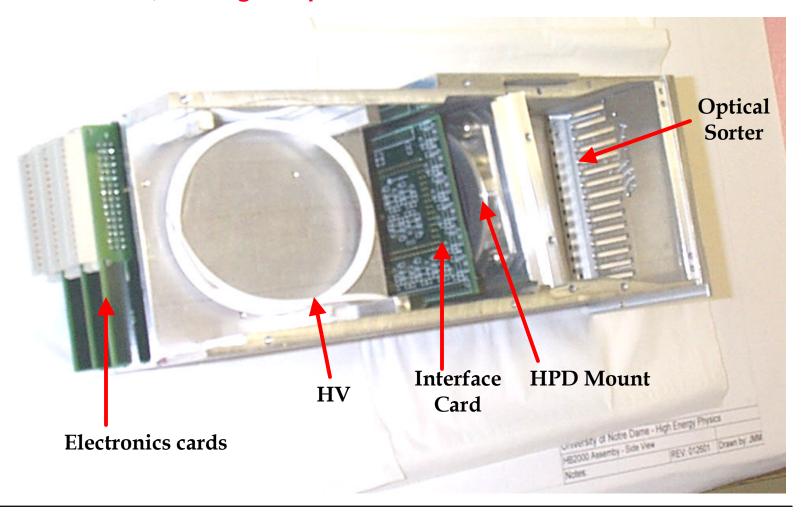




### RM19 Sidewall removed

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• The readout module (RM) integrates the HPD, front end electronics, and digital optical drivers.

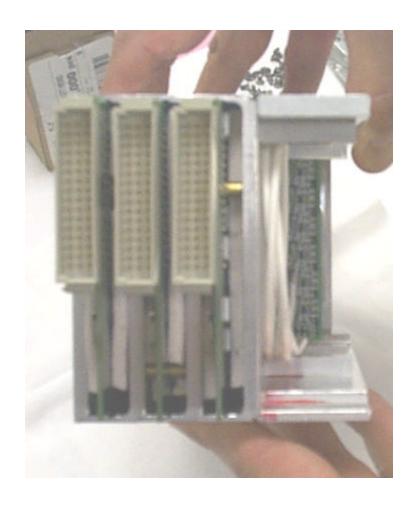




## **RM19 Rear and Front Views**

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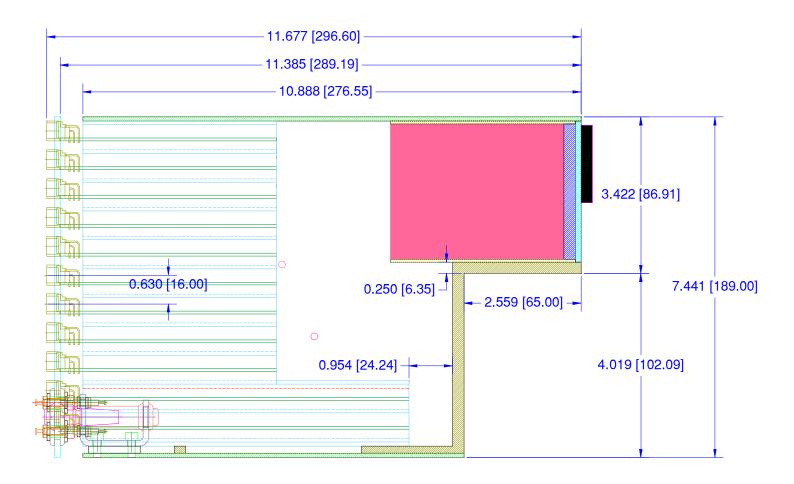






## **RM-73**

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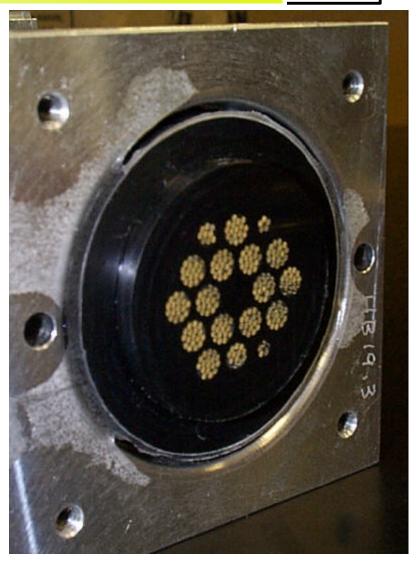


## **ODU Construction - '01**

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## The Hybrid Photodiode (HPD)



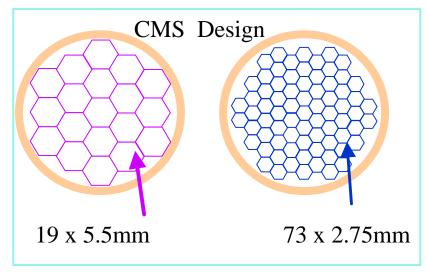
### **Tube Fabrication by Delft Electronic Products (Netherlands)**

Subcontracts: Canberra (Belgium) 22% for diodes

Schott Glass (USA) 8% for fiber optic windows

Kyocera (Japan) 4% for vacuum feedthru/ceramic carrier





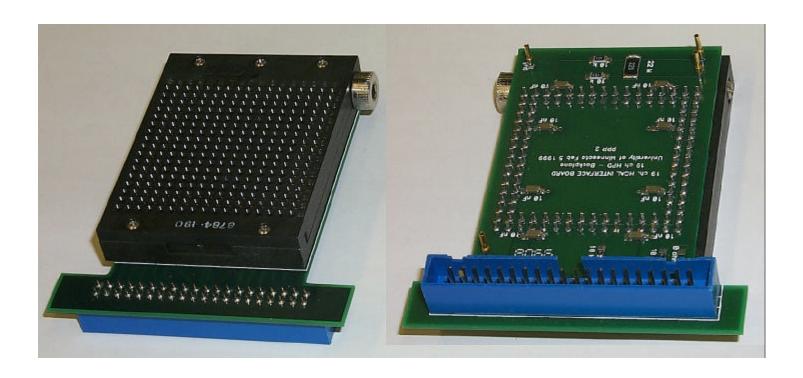
- 12 kV across 3.5 mm gap with  $V_{th} < 3 \text{ kV} => \text{Gain of } 2500$
- Silicon PIN diode array, T-type
- Thin (200 µm) with 100 V reverse bias for fast charge (holes) collection



## **HPD Interface Board**

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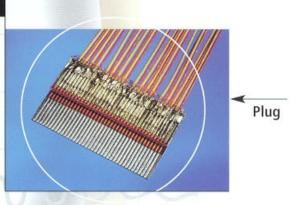
## Signal Cable Candidate(1)

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#### **PICO-FLEX®**

#### OR USE PICO-FLEX:

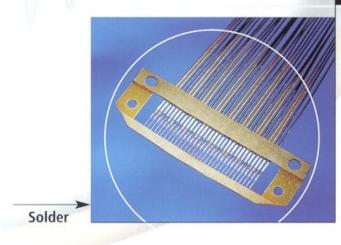
- · Mounted in a ZIF connector surface mounted on a PCB.
- Available in 0,5 mm pitch (0,019").
- . Compatible with PICO-COAX® AWG 40 to 46 (50 and 100 pF/m, 15 and 30 pF/ft).
  - · Custom designed versions available on request.



### PICO-WELD®

#### **USE PICO-WELD®:**

- Solders directly to PC board.
- · Maintains alignment of the PICO-COAX® at a constant pitch.
- · Hot bar system soldering.
- · Available in 32 positions pitch 0,635 mm (0,025").
- Compatible with AWG 40 and 42 (50 and 100 pF/m, 15 and 30 pF/ft).
- · Other constructions available on request





## Signal Cable Candidate(2)



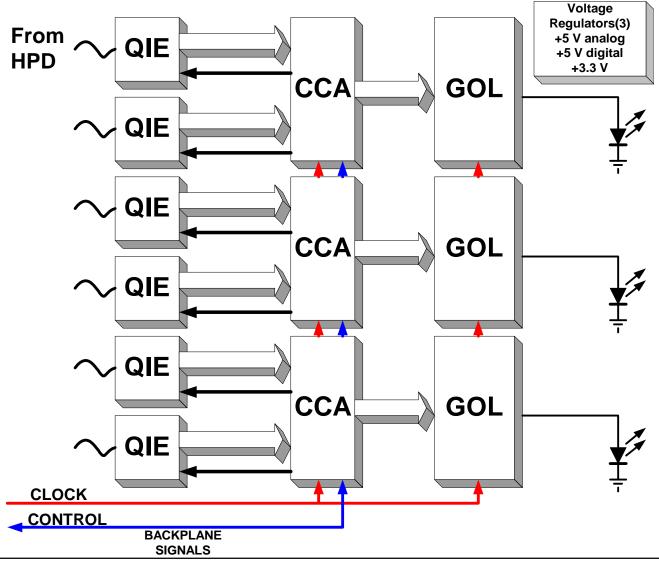


**GET CABLE/CONNECTOR SPECS** 



## **Block Diagram of FE Card**

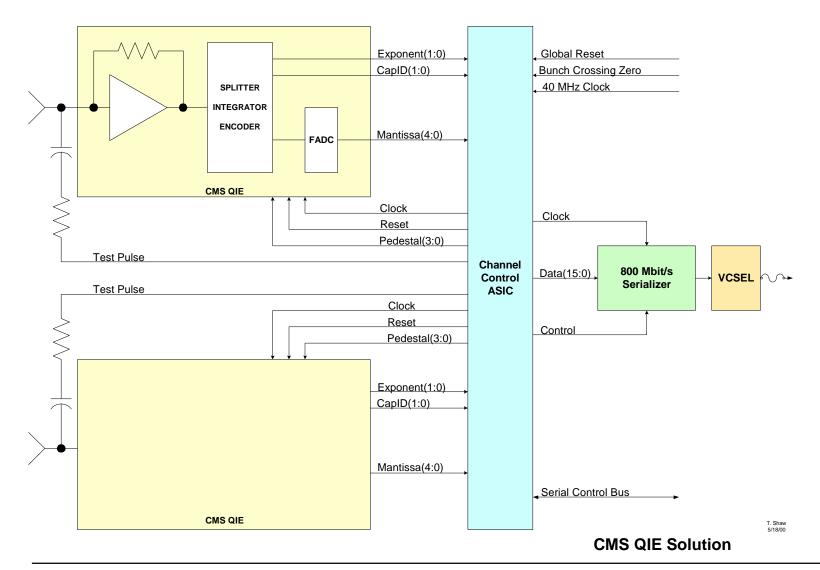
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### **FE Channels**

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## **QIE Description**

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### QIE

### **Charge Integrator Encoder**

4 stage pipelined device (25ns per stage)

charge collection

settling

readout

reset

Inverting (HPDs) and Non-inverting (PMTs) Inputs

Internal non-linear Flash ADC

Outputs

5 bit mantissa

2 bit range exponent

2 bit Cap ID



## **QIE Specification**

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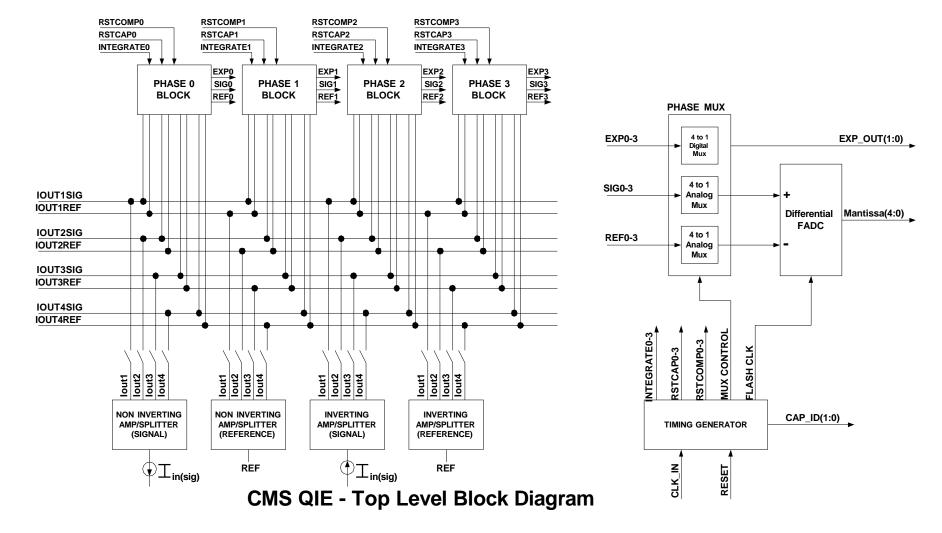
### **QIE Design Specifications**

- Clock > 40 MHz
- Must have inverting and non-inverting inputs
- Charge sensitivity of lowest range 1fC/LSB
  - In Calibration Mode 1/3 fC/LSB
- Maximum Charge 9670 fC/25ns
- 4500 electrons rms noise
- FADC Differential Non-Linearity < .05 LSBs</li>



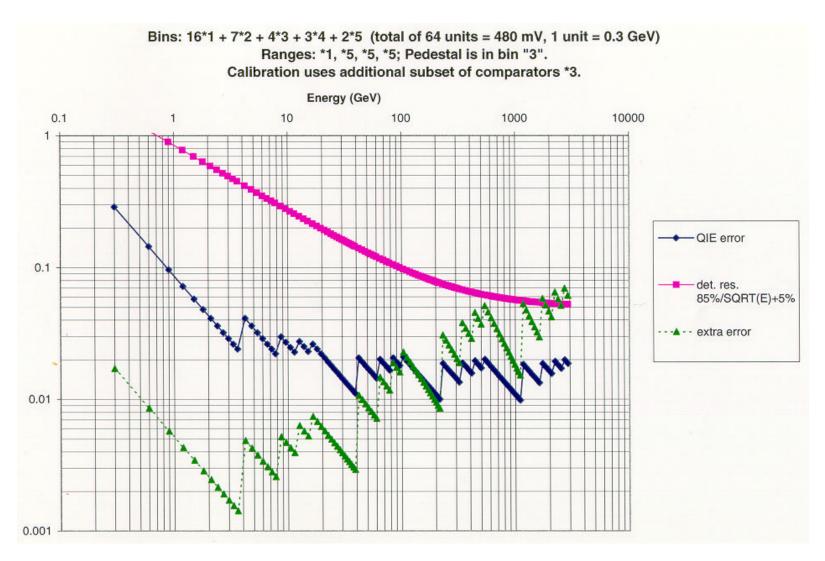
## QIE Functional Block Diagram – Top Level







## **FLASH ADC Quantization**



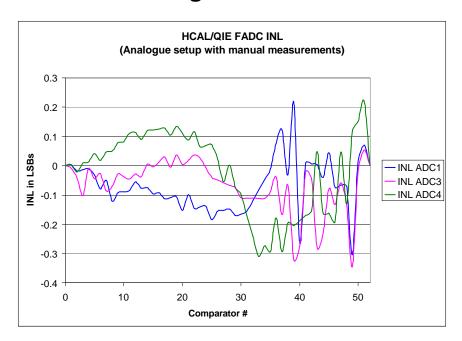


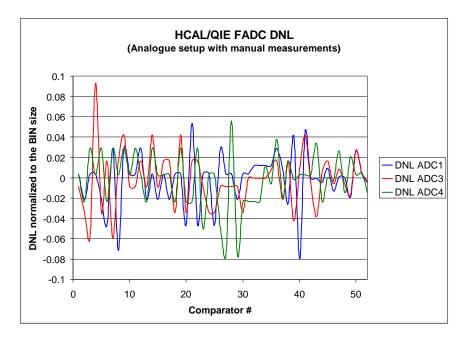
### **QIE Status**

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### **QIE ASIC**

- Current splitter design submitted and tested
- Input amplifier with polarity and gain adjust submitted and tested
- Non-linear Flash ADC design submitted and tested
- Full design submitted back mid to late June '01







# **QIE Schedule**

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Task Name	Q-4	Finish	Downting	2000 20	001	2002			
	Start	Finish	Duration		Jan Apr Jul Oct	Jan Apr Jul Oct			
AMS splitter test chip	Mon 11/2/98	Fri 4/30/99	130 days 💠	S Splitter Test Chip					
Test Splitter	Mon 8/30/99	Fri 10/29/99	45 days	Test Splitter					
RAD Testing	Mon 11/1/99	Fri 3/3/00	90 days	RAD Testing					
AMP w/ polarity and gain adjust	Mon 6/28/99	Fri 10/1/99	70 days	AMP w/ polarity and gain adjust					
FAB AMP w/ polarity and gain adjus	Mon 10/4/99	Fri 4/14/00	140 days	FAB AMP w/ polarity	y and gain adjust				
Test AMP w/ polarity and gain adjus	Mon 5/29/00	Fri 6/30/00	25 days	Test AMP w/p	polarity and gain adjust				
ADC for 4 range splitter	Mon 8/30/99	Fri 1/28/00	110 days	ADC for 4 range splitter					
FAB ADC for 4 range Splitter	Tue 2/1/00	Mon 5/15/00	75 days	FAB ADC for 4 ran	ige Splitter				
Test ADC for 4 range splitter	Mon 7/3/00	Fri 8/11/00	30 days	Test ADC fo	or 4 range splitter				
New Amp	Mon 2/28/00	Fri 3/31/00	25 days	New Amp					
FAB new Amp	Mon 4/3/00	Fri 7/14/00	75 days	FAB new Amj	P				
Test new Amp	Mon 7/31/00	Fri 9/1/00	25 days	Test new	Amp				
Full CMS QIE Design	Mon 3/27/00	Mon 3/5/01	246 days		Full CMS QIE Design				
FAB Full CMS QIE	Mon 3/5/01	Fri 6/15/01	75 days		FAB Full CMS	QIE			
Test Full CMS QIE	Mon 7/2/01	Fri 8/24/01	40 days		Test Ful	ECMS QIE			
Mod Full CMS QIE	Mon 7/16/01	Fri 10/19/01	70 days		Mod	Full CMS QIE			
FAB Eng/Prod Run	Mon 10/22/01	Fri 2/1/02	75 days			FAB Eng/Prod Run			
Test Eng/Prod Run	Mon 2/4/02	Fri 3/15/02	30 days			Test Eng/Prod Rui			
PROD Mods	Mon 3/18/02	Fri 4/12/02	20 days			PROD Mods			
PROD Fab	Mon 4/15/02	Fri 7/26/02	75 days			PROD Fa			
Production Contingency	Mon 7/29/02	Fri 11/8/02	75 days		Production	Contingency			



## **Channel Control ASIC**

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The CCA provides the following functions:

- The processing and synchronization of data from two QIEs,
- The provision of phase-adjusted QIE clocking signals to run the QIE charge integrator and Flash ADC,
- Checking of the accuracy of the Capacitor IDs, the Cap IDs from different QIEs should be in synchronization,
- The ability to force the QIE to use a given range,
- The ability to set Pedestal DAC values,
- The ability to issue a test pulse trigger,
- The provision of event synchronization checks a crossing counter will be implemented and checked for accuracy with every beam turn marker,
- The ability to send a known pattern to the serial optic link,
- The ability to "reset" the QIE at a known and determined time,
- And, the ability to send and report on any detected errors at a known and determined time.

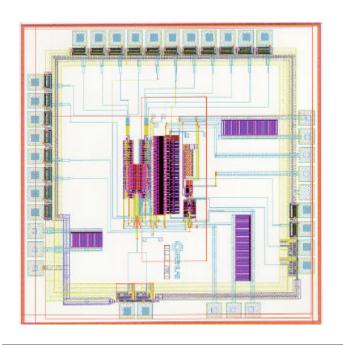


## **CCA Status**

Η Α

## **Channel Control ASIC**

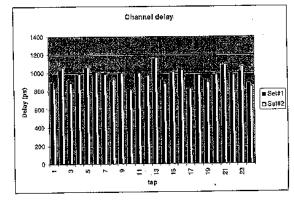
- DLL for timing control submitted and tested
- 1ns multiplexer design submitted and tested
- Serial Interface design submitted and tested



#### Measured delays vs. tap

· Average delay: 972p STD:77ps 810p Min delay:

Max delay: 1170p





# **CCA Schedule**

Н A

ask Name	Start	Finish	Duration		199			2000			2001				2002				2003	
200000000000000000000000000000000000000		FILIISTI		Oct	Jan			Jan Apr		Oct	Jan	Apr	Jul	Oct	Jan	Apr	Jul	Oct	Jan	Apr Jul
Fab Phase Locked Loop	Mon 1/4/99	Fri 4/9/99	70 days			Fab Dela	ay Lo	cked Loop	)										4	
Test Phase Lock Loop	Mon 4/26/99	Fri 7/30/99	70 days			To	est Pl	nase Lock	Loo	Р										
Design 3 Channel PLL and	Mon 8/2/99	Fri 10/29/99	65 days			10	De	sign 3 Ch	anne	I PLL	and	Mux								
Fab 3 Channel PLL and Mu	Mon 11/1/99	Fri 2/4/00	70 days			45		Fab 3 C	hanr	iel PL	L an	Mu	ıx						ŝ	
Test 3 Channel PLL And M	Mon 2/7/00		40 days							nanne				x					i i	
Rad Test, SEU Study	Mon 4/3/00	20050500000	90 days							d Te										
Design Interface Protocol	Tue 8/31/99	Mon 7/3/00	220 days						Des	ign Ir	iterfa	ce F	roto	col						
Fab Interface Protocol	Mon 9/4/00	Fri 12/8/00	70 days							- 1	ab Ir	terf	ace F	roto	col					
Test Interface Protocol	Mon 1/1/01	Fri 2/23/01	40 days								Т	est I	nteri	face I	Proto	col				
Design Full CCA	Mon 9/4/00	Fri 5/25/01	190 days										esig	n Ful	li CC	Ą				
Fab Full CCA	Mon 5/28/01	Fri 8/3/01	50 days										Fa	b Ful	I CC	A			3	
Test Full CCA	Mon 8/6/01	Fri 9/28/01	40 days											Tes	t Full	CCA				
Design Mods for Engineerii	Mon 9/3/01	Fri 11/23/01	60 days												esig	n Mo	ds fo	or En	gined	ering Rui
Fab Engineering Run	Mon 11/26/01	Fri 2/1/02	50 days											- 144	Fa	b Eng	qinee	ering	Run	
Test Engineering Run	Mon 2/4/02	311115	60 days														ij		Š	g Run
Test with CMS QIE	Mon 2/18/02	70.000.000.000.000	60 days															rith C	100	
CCA Production	Mon 5/13/02	Fri 8/16/02	70 days									(	CCAI	Prod	uctio	n <mark>=</mark>				



# QIE/CCA Process Reliability

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## AMS 0.8u BiCMOS Process (QIE)

Early Failure rate 0.05 - 0.2%; can be reduced to a few ppm by burn-in

Predicted MTTF (25 sqmm, 55 C) is 1.67E8 hours

**Expect less than 1 QIE failure per year** 

## **HP/Agilent 0.5u CMOS**

**Well established Commercial Process** 



# GOL Design Specifications

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#### Synchronous (constant latency)

### **Transmission speed**

- fast: 1.6 Gbps , 32 bit data input @ 40 MHz
- slow: 0.8 Gbps , 16 bit data input @ 40 MHz

#### Two encoding schemes

- G-Link
- Fiber channel (8B/10B)

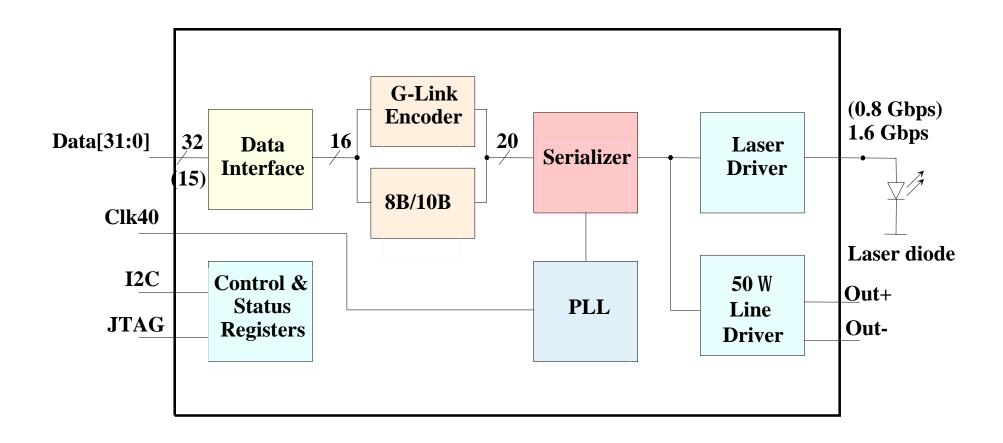
### Interfaces for control and status registers

- 12C
- JTAG



## Gigabit link (G-Link, 8B/10B optional)

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# **GOL Radiation hardness**

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Deep submicron (0.25 um) CMOS Enclosed CMOS transistors

Triple voting in state machines
Up-sizing of PLL components
Auto-error correction in Config. registers

## Single Event Upsets

#### Can we extrapolate for LHC?

CMS Environment	Pixel R = 4 – 20cm	Endcap ECAL R = 50 - 130cm	Tracker R = 65-120cm	Cavern R = 700 - 1200cm
Error/(chip hour)	1.4 10 <sup>-2</sup>	1.9 10 <sup>-4</sup>	8.4 10 <sup>-5</sup>	3.1 10 <sup>-8</sup>
#chips for one error each hour!	71	5.3K	12K	32M



## **GOL Status**

H C A L

- Bit error rate test in the 800Mbit/s G-Link mode: 20 hours error free transmission (external laser driver).
- Bit error rate test in the 1.6Gbit/s 8B/10B mode: 13 hours error free transmission (external laser driver).
- I2C interface successfully tested.
- JTAG interface successfully tested.
- Need to understand and fix jitter problem on internal laser driver. This will be fixed in the next submission (April '01).



## **VCSEL Selection**

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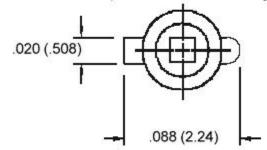
#### HFE4086-001

VCSEL Components, Data Communications, Flat Window Pillpack, Unattenuate optics, no back monitor photodiode

#### FEATURES

- Designed for drive currents between 5 mA and 15 mA
- Optimized for low dependence of electrical properties over temperature
- High speed > 1 Ghz
- · Miniature flat-window, pill-pack package

#### MOUNTING DIMENSIONS (for reference only): in./(mm)







## **VCSEL Mechanics**

Η  $\mathbf{C}$ Α

Assembly **PCBoard** Cin::apse Connector VCSELs & Fibers Connector mold **PCBoard** Cin::apse Connector VCSELs & Fibers Connector mold



# Rad Tolerant Voltage Regulator

Η  $\mathbf{C}$  $\mathbf{A}$ 

**Developed by ST Microelectronics Specified by CERN RD49** 

Shown to be Rad Hard

**Presently fixing overvoltage protection** 

**Prepreduction parts due June 2001** 

**Production parts late 2001??** 

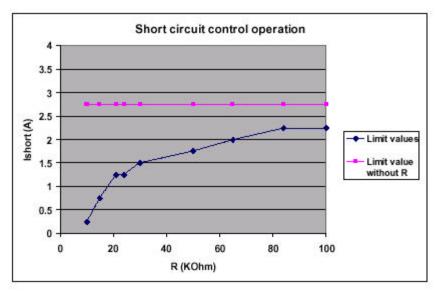
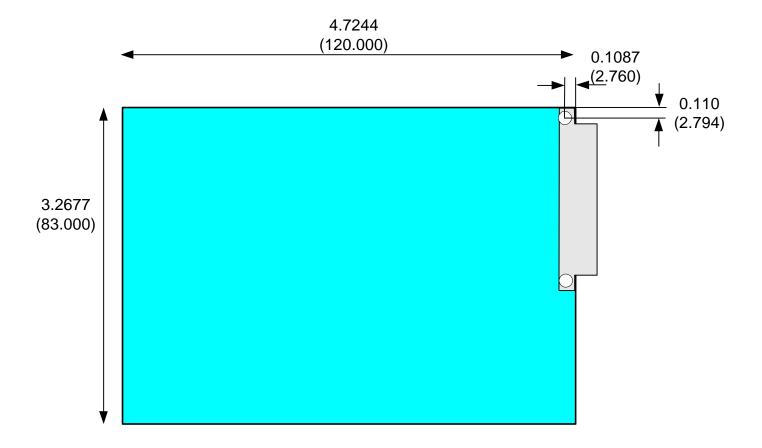


Fig. 7: Tuning of the maximum output current in a 2<sup>nd</sup> edition prototype regulator (version 2.5 V).



# **Readout Card Dimension**

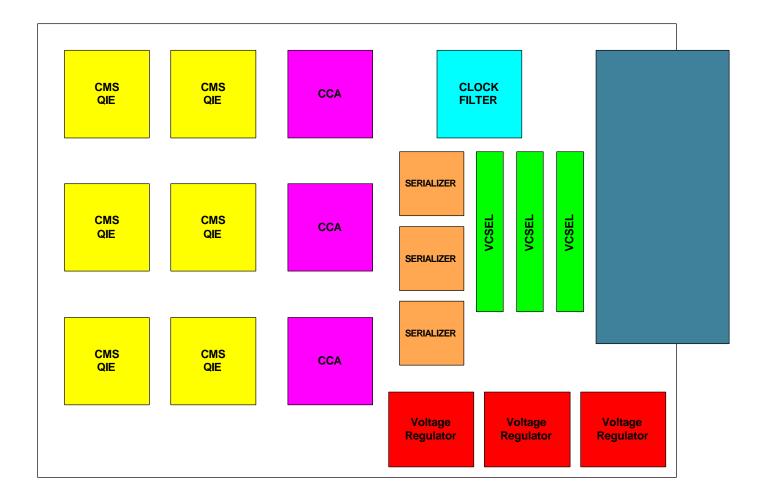
 $\mathbf{C}$ Α





# **FE Card Component Area**

Α

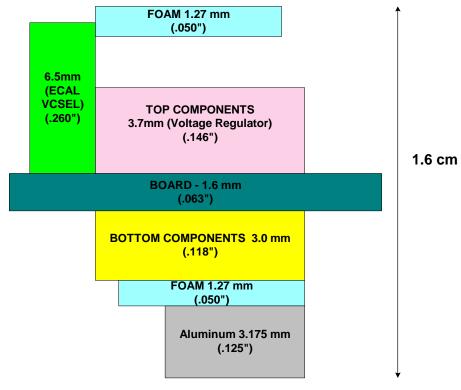




# Readout Card **Component Height**



#### Goal is 1.6 cm stack

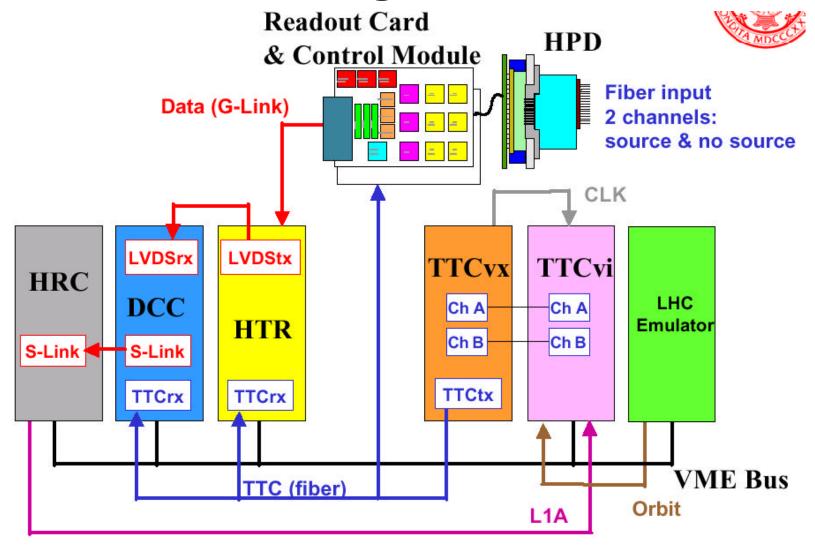


**Geometric Space For Components** 



# Plan for FE/HTR Integration

H C A L





## Summary

Η  $\mathbf{C}$ Α

## **FE/DAQ** integration planned for this fall

- 2 channel FF card
  - 2 QIEs
  - Commercial G-Link (@800 Mb/s)
- 6U HTR card
- 9U DCC module

## Next – ready for summer 2002 test beam

- 6 channel FE card
  - 6 QIEs
  - Rad hard Voltage Regulator
  - GOL (8B/10B Encoding @1.6Gb/s)
  - Custom VCSEL package
  - CCA